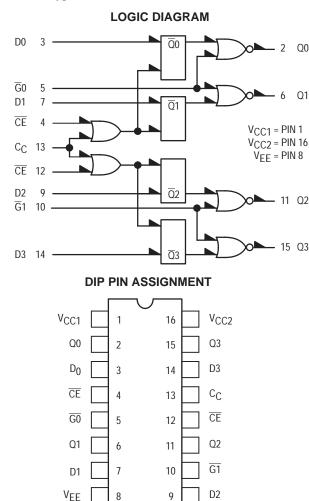
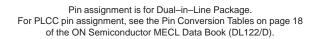
Quad Latch

The MC10133 is a high speed, low power, quad latch consisting of four bistable latch circuits with D type inputs and gated Q outputs, allowing direct wiring to a bus. When the clock is high, outputs will follow D inputs. Information is latched on the negative going transition of the clock.

The outputs are gated when the output enable (\overline{G}) is low. All four latches may be clocked at one time with the common clock (C_C), or each half may be clocked separately with its clock enable (\overline{CE}).

- P_D=310 mW typ/pkg (No Load)
- t_{pd} = 4.0 ns typ
- t_r , $t_f=2.0$ ns typ (20%-80%)

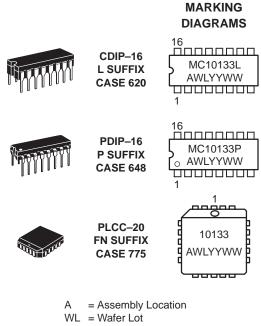






ON Semiconductor

http://onsemi.com



WL = Wafer Lot YY = Year

WW = Work Week

Т	RUTI	H TA	BLE

G	С	D	Q _{n+1}
Н	Х	Х	L
L	L	Х	Q _n
L	Н	L	L
L	Н	Н	Н

C = CC = CE

ORDERING INFORMATION

Device	Package	Shipping
MC10133L	CDIP-16	25 Units / Rail
MC10133P	PDIP-16	25 Units / Rail
MC10133FN	PLCC-20	46 Units / Rail

ELECTRICAL CHARACTERISTICS

			Test Limits							
		Pin Under	Pin –30°C		+25°C			+8	5°C	1
Characteristic	Symbol	Test	Min	Max	Min	Тур	Max	Min	Max	Unit
Power Supply Drain Current	١E	8		82			75		82	mAdd
Input Current	linH	3 4 5 13		390 425 560 560			245 265 350 350		245 265 350 350	μAdc
	linL	3	0.5		0.5			0.3		μAdc
Output Voltage Logic 1	VOH	2 2	-1.060 -1.060	-0.890 -0.890	-0.960 -0.960		-0.810 -0.810	-0.890 -0.890	-0.700 -0.700	Vdc
Output Voltage Logic 0	V _{OL}	2 2 2	-1.890 -1.890 -1.890	-1.675 -1.675 -1.675	-1.850 -1.850 -1.850		-1.650 -1.650 -1.650	-1.825 -1.825 -1.825	-1.615 -1.615 -1.615	Vdc
Threshold Voltage Logic 1	Voha	2 2 2† 2‡ 2 2 2 2 2	-1.080 -1.080 -1.080 -1.080 -1.080 -1.080 -1.080 -1.080		-0.980 -0.980 -0.980 -0.980 -0.980 -0.980 -0.980 -0.980			-0.910 -0.910 -0.910 -0.910 -0.910 -0.910 -0.910 -0.910		Vdc
Threshold Voltage Logic 0	Vola	2 2 2† 2‡ 2‡		-1.655 -1.655 -1.655 -1.655 -1.655 -1.655 -1.655			-1.630 -1.630 -1.630 -1.630 -1.630 -1.630		-1.595 -1.595 -1.595 -1.595 -1.595 -1.595 -1.595	Vdc
Switching Times (50 Ω Load)										ns
Propagation Delay	^t 3+2+ ^t 4+2+ ^t 5–2+ ^t setup ^t hold	2 2 3 3	1.0 1.0 1.0 2.5 1.5	5.6 5.4 3.2	1.0 1.0 1.0 2.5 1.5	4.0 4.0 2.0 0.7 0.7	5.4 5.4 3.1	1.1 1.2 1.0 2.5 1.5	5.9 6.0 3.4	
Rise Time (20 to 80%)	t2+	2	1.0	3.6	1.1	2.0	3.5	1.1	3.8	
Fall Time (20 to 80%)	t2-	2	1.0	3.6	1.1	2.0	3.5	1.1	3.8	

 \dagger Output level to be measured after a clock pulse has been applied to the clock input (Pin 4)

─── V_{IHmax} · ── V_{ILmin}

Data input at proper high/low level while clock pulse is high so that device latches ar proper high/low level for test. Levels are measured after device has latched.

* Latch set to zero state before test.

ELECTRICAL CHARACTERISTICS (continued)

		TEST VOLTAGE VALUES (Volts)							
		@ Test Te	mperature	V _{IHmax}	V _{ILmin}	VIHAmin	VILAmax	VEE	
			−30°C	-0.890	-1.890	-1.205	-1.500	-5.2	1
		+25°C		-0.810	-1.850	-1.105	-1.475	-5.2	1
			+85°C	-0.700	-1.825	-1.035	-1.440	-5.2	1
			Pin	TEST	/OLTAGE A		PINS LISTED E	BELOW	1
Character	istic	Symbol	Under Test	V _{IHmax}	V _{ILmin}	VIHAmin	VILAmax	VEE	(VCC) Gnd
Power Supply Drain (Current	١ _E	8		13			8	1, 16
Input Current		linH	3	3				8	1, 16
			4	4				8	1, 16
			5 13	5 13				8 8	1, 16 1, 16
		linL	3	10	3			8	1, 16
				2.4	5			8	
Output Voltage	Logic 1	VOH	2 2	3, 4 3, 13				8 8	1, 16 1, 16
Output Voltage	Logic 0	VOL	2	13	3			8	1, 16
			2	3, 5, 13				8	1, 16
			2	4	3			8	1, 16
Threshold Voltage	Logic 1	Vона	2 2	3, 4 4		3	5	8 8	1, 16 1, 16
			2	3, 4		5		8	1, 16
			2†	3				8	1, 16
			2‡					8	1, 16
			2‡				4	8	1, 16
			2 2	3		4 13		8 8	1, 16 1, 16
Threshold Voltage	Logic 0	VOLA	2	3, 4		5		8	1, 16
ge	9		2	4			3	8	1, 16
			2	4				8	1, 16
			2†					8	1, 16
			2‡ 2‡	3 3			13	8 8	1, 16 1, 16
Switching Times	(50Ω Load)			+1.11V		Pulse In	Pulse Out	–3.2 V	+2.0 \
Propagation Delay		t3+2+	2	4	1	3	2	8	1, 16
		t4+2+	2	3*		4	2	8	1, 16
		^t 5–2+	2			5	2	8	1, 16
		^t setup ^t hold	3 3			3 3	2 2	8 8	1, 16 1, 16
Rise Time	(20 to 80%)	t ₂₊	2	4		3	2	8	1, 16
Fall Time	(20 to 80%)	t2-	2	4		3	2	8	1, 16

[†]Output level to be measured after a clock pulse has been applied to the clock input (Pin 4)

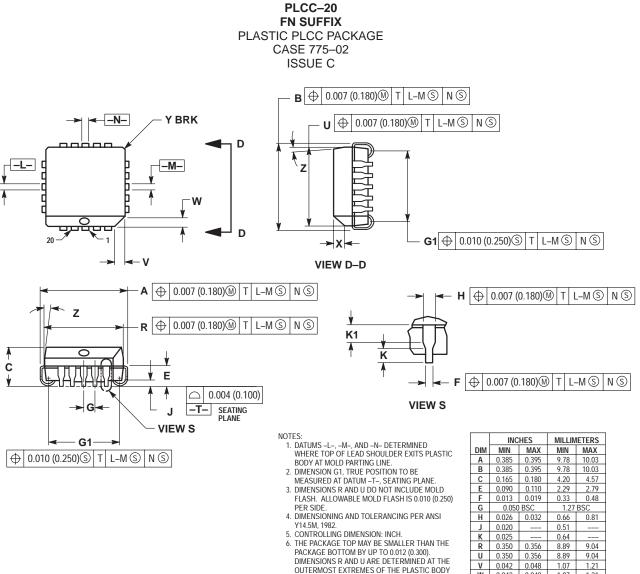
· — V_{IHmax} · — V_{ILmin}

Data input at proper high/low level while clock pulse is high so that device latches ar proper high/low level for test. Levels are measured after device has latched.

* Latch set to zero state before test.

Each MECL 10,000 series circuit has been designed to meet the dc specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Outputs are terminated through a 50–ohm resistor to –2.0 volts. Test procedures are shown for only one gate. The other gates are tested in the same manner.

PACKAGE DIMENSIONS



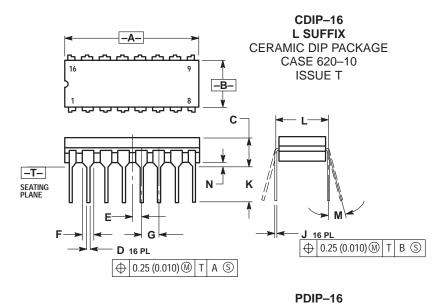
OUTERMOST EXTREMES OF THE PLASTIC BODY EXCLUSIVE OF MOLD FLASH, TIE BAR BURRS, GATE BURRS AND INTERLEAD FLASH, BUT INCLUDING ANY MISMATCH BETWEEN THE TOP INCLUDING ANY MISMATCH BE IWEEN THE TOP AND BOTTOM OF THE PLASTIC BODY. 7. DIMENSION H DOES NOT INCLUDE DAMBAR PROTRUSION OR INTRUSION. THE DAMBAR PROTRUSION(S) SHALL NOT CAUSE THE H DIMENSION TO BE GREATER THAN 0.037 (0.940).

THE DAMBAR INTRUSION(S) SHALL NOT CAUSE THE H DIMENSION TO BE SMALLER THAN 0.025

В	0.385	0.395	9.78	10.03
С	0.165	0.180	4.20	4.57
Ε	0.090	0.110	2.29	2.79
F	0.013	0.019	0.33	0.48
G	0.050	BSC	1.27	BSC
Н	0.026	0.032	0.66	0.81
J	0.020		0.51	
K	0.025		0.64	
R	0.350	0.356	8.89	9.04
U	0.350	0.356	8.89	9.04
٧	0.042	0.048	1.07	1.21
W	0.042	0.048	1.07	1.21
Х	0.042	0.056	1.07	1.42
Y		0.020		0.50
Z	2 °	10 °	2 °	10 °
G1	0.310	0.330	7.88	8.38
K1	0.040		1.02	

(0.635).

PACKAGE DIMENSIONS



NOTES: 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982. 2. CONTROLLING DIMENSION: INCH. 3. DIMENSION L TO CENTER OF LEAD WHEN FORMED PARALLEL. 4. DIMENSION F MAY NARROW TO 0.76 (0.030) WHERE THE LEAD ENTERS THE CERAMIC BODY.

	INC	HES	MILLIMETERS		
DIM	MIN MAX		MIN	MAX	
Α	0.750	0.785	19.05	19.93	
В	0.240	0.295	6.10	7.49	
С		0.200		5.08	
D	0.015	0.020	0.39	0.50	
Е	0.050	BSC	1.27 BSC		
F	0.055	0.055 0.065		1.65	
G	0.100	BSC	2.54 BSC		
Н	0.008	0.015	0.21	0.38	
К	0.125	0.170	3.18	4.31	
L	0.300	BSC	7.62	BSC	
Μ	0 °	15°	0 °	15 °	
Ν	0.020	0.040	0.51	1.01	

P SUFFIX PLASTIC DIP PACKAGE CASE 648-08 -A-ISSUE R 16 В 0 Ú ᇇᇇᇇ Ų ۲ կ , լ F - C S -T- SEATING PLANE κ H → н G **D** 16 PL ⊕ 0.25 (0.010) M T A M

NOTES: 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982. 2. CONTROLLING DIMENSION: INCH. 3. DIMENSION L TO CENTER OF LEADS WHEN FORMED PARALLEL. 4. DIMENSION B DOES NOT INCLUDE MOLD FLASH. 5. ROUNDED CORNERS OPTIONAL.

	INC	HES	MILLIM	ETERS	
DIM	MIN	MAX	MIN	MAX	
Α	0.740	0.770	18.80	19.55	
В	0.250	0.270	6.35	6.85	
С	0.145	0.175	3.69	4.44	
D	0.015	0.021	0.39	0.53	
F	0.040	0.70	1.02	1.77	
G	0.100	BSC	2.54 BSC		
Н	0.050	BSC	1.27 BSC		
J	0.008	0.015	0.21	0.38	
К	0.110	0.130	2.80	3.30	
L	0.295	0.305	7.50	7.74	
Μ	0°	10 °	0 °	10 °	
S	0.020	0.040	0.51	1.01	

<u>Notes</u>

Notes

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